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Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	667MHz
Co-Processors/DSP	Communications; QUICC Engine, Security; SEC
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	740-LBGA
Supplier Device Package	740-TBGA (37.5x37.5)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8360ezualfg

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

This table provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings¹

Characteristic		Symbol	Max Value	Unit	Notes
Core and PLL supply voltage for MPC8358 Device Part Number with Processor Frequency label of AD=266MHz and AG=400MHz & QUICC Engine Frequency label of E=300MHz & G=400MHz MPC8360 Device Part Number with Processor Frequency label of AG=400MHz and AJ=533MHz & QUICC Engine Frequency label of G=400MHz		V_{DD} & AV_{DD}	–0.3 to 1.32	V	—
Core and PLL supply voltage for MPC8360 device Part Number with Processor Frequency label of AL=667MHz and QUICC Engine Frequency label of H=500MHz		V_{DD} & AV_{DD}	–0.3 to 1.37	V	—
DDR and DDR2 DRAM I/O voltage		GV_{DD}	–0.3 to 2.75	V	—
	DDR DDR2		–0.3 to 1.89		
Three-speed Ethernet I/O, MII management voltage		LV_{DD}	–0.3 to 3.63	V	—
PCI, local bus, DUART, system control and power management, I ² C, SPI, and JTAG I/O voltage		OV_{DD}	–0.3 to 3.63	V	—
Input voltage	DDR DRAM signals	MV_{IN}	–0.3 to ($GV_{DD} + 0.3$)	V	2, 5
	DDR DRAM reference	MV_{REF}	–0.3 to ($GV_{DD} + 0.3$)	V	2, 5
	Three-speed Ethernet signals	LV_{IN}	–0.3 to ($LV_{DD} + 0.3$)	V	4, 5
	Local bus, DUART, CLKIN, system control and power management, I ² C, SPI, and JTAG signals	OV_{IN}	–0.3 to ($OV_{DD} + 0.3$)	V	3, 5
	PCI	OV_{IN}	–0.3 to ($OV_{DD} + 0.3$)	V	6

This table shows the estimated typical I/O power dissipation for the device.

Table 6. Estimated Typical I/O Power Dissipation

Interface	Parameter	GV _{DD} (1.8 V)	GV _{DD} (2.5 V)	OV _{DD} (3.3 V)	LV _{DD} (3.3 V)	LV _{DD} (2.5 V)	Unit	Comments
DDR I/O 65% utilization R _s = 20 Ω R _t = 50 Ω 2 pairs of clocks	200 MHz, 1 × 32 bits	0.3	0.46	—	—	—	W	—
	200 MHz, 1 × 64 bits	0.4	0.58	—	—	—	W	—
	200 MHz, 2 × 32 bits	0.6	0.92	—	—	—	W	—
	266 MHz, 1 × 32 bits	0.35	0.56	—	—	—	W	—
	266 MHz, 1 × 64 bits	0.46	0.7	—	—	—	W	—
	266 MHz, 2 × 32 bits	0.7	1.11	—	—	—	W	—
	333 MHz, 1 × 32 bits	0.4	0.65	—	—	—	W	—
	333 MHz, 1 × 64 bits	0.53	0.82	—	—	—	W	—
	333 MHz, 2 × 32 bits	0.81	1.3	—	—	—	W	—
Local Bus I/O Load = 25 pF 3 pairs of clocks	133 MHz, 32 bits	—	—	0.22	—	—	W	—
	83 MHz, 32 bits	—	—	0.14	—	—	W	—
	66 MHz, 32 bits	—	—	0.12	—	—	W	—
	50 MHz, 32 bits	—	—	0.09	—	—	W	—
PCI I/O Load = 30 pF	33 MHz, 32 bits	—	—	0.05	—	—	W	—
	66 MHz, 32 bits	—	—	0.07	—	—	W	—
10/100/1000 Ethernet I/O Load = 20 pF	MII or RMII	—	—	—	0.01	—	W	Multiply by number of interfaces used.
	GMII or TBI	—	—	—	0.04	—	W	
	RGMII or RTBI	—	—	—	—	0.04	W	
Other I/O	—	—	—	0.1	—	—	W	—

4 Clock Input Timing

This section provides the clock input DC and AC electrical characteristics for the MPC8360E/58E.

NOTE

The rise/fall time on QUICC Engine block input pins should not exceed 5 ns. This should be enforced especially on clock signals. Rise time refers to signal transitions from 10% to 90% of V_{DD}; fall time refers to transitions from 90% to 10% of V_{DD}.

4.1 DC Electrical Characteristics

This table provides the clock input (CLKIN/PCI_SYNC_IN) DC timing specifications for the device.

Table 7. CLKIN DC Electrical Characteristics

Parameter	Condition	Symbol	Min	Max	Unit
Input high voltage	—	V_{IH}	2.7	$OV_{DD} + 0.3$	V
Input low voltage	—	V_{IL}	−0.3	0.4	V
CLKIN input current	$0\text{ V} \leq V_{IN} \leq OV_{DD}$	I_{IN}	—	±10	μA
PCI_SYNC_IN input current	$0\text{ V} \leq V_{IN} \leq 0.5\text{ V}$ or $OV_{DD} - 0.5\text{ V} \leq V_{IN} \leq OV_{DD}$	I_{IN}	—	±10	μA
PCI_SYNC_IN input current	$0.5\text{ V} \leq V_{IN} \leq OV_{DD} - 0.5\text{ V}$	I_{IN}	—	±100	μA

4.2 AC Electrical Characteristics

The primary clock source for the device can be one of two inputs, CLKIN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. This table provides the clock input (CLKIN/PCI_CLK) AC timing specifications for the device.

Table 8. CLKIN AC Timing Specifications

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
CLKIN/PCI_CLK frequency	f_{CLKIN}	—	—	66.67	MHz	1
CLKIN/PCI_CLK cycle time	t_{CLKIN}	15	—	—	ns	—
CLKIN/PCI_CLK rise and fall time	t_{KH}, t_{KL}	0.6	1.0	2.3	ns	2
CLKIN/PCI_CLK duty cycle	t_{KHK}/t_{CLKIN}	40	—	60	%	3
CLKIN/PCI_CLK jitter	—	—	—	±150	ps	4, 5

Notes:

- Caution:** The system, core, USB, security, and 10/100/1000 Ethernet must not exceed their respective maximum or minimum operating frequencies.
- Rise and fall times for CLKIN/PCI_CLK are measured at 0.4 V and 2.7 V.
- Timing is guaranteed by design and characterization.
- This represents the total input jitter—short term and long term—and is guaranteed by design.
- The CLKIN/PCI_CLK driver's closed loop jitter bandwidth should be <500 kHz at −20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track CLKIN drivers with the specified jitter.

4.3 Gigabit Reference Clock Input Timing

This table provides the Gigabit reference clocks (GTX_CLK125) AC timing specifications.

Table 9. GTX_CLK125 AC Timing Specifications

At recommended operating conditions with $LV_{DD} = 2.5 \pm 0.125\text{ mV}$ / $3.3\text{ V} \pm 165\text{ mV}$

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
GTX_CLK125 frequency	t_{G125}	—	125	—	MHz	—
GTX_CLK125 cycle time	t_{G125}	—	8	—	ns	—

Table 21. DDR and DDR2 SDRAM Output AC Timing Specifications for Source Synchronous Mode (continued)

At recommended operating conditions with GV_{DD} of (1.8 V or 2.5 V) $\pm$ 5%.

Parameter ⁸	Symbol ¹	Min	Max	Unit	Notes
MDQS epilogue end	t_{DDKHME}	-0.6	0.9	ns	7

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
- All MCK/MCK referenced measurements are made from the crossing of the two signals ± 0.1 V.
- In the source synchronous mode, MCK/MCK can be shifted in $\frac{1}{4}$ applied cycle increments through the clock control register. For the skew measurements referenced for t_{AOSKEW} it is assumed that the clock adjustment is set to align the address/command valid with the rising edge of MCK.
- ADDR/CMD includes all DDR SDRAM output signals except $\overline{MCK}/\overline{MCK}$, $\overline{MCS}$, and MDQ/MECC/MDM/MDQS. For the ADDR/CMD setup and hold specifications, it is assumed that the clock control register is set to adjust the memory clocks by $\frac{1}{2}$ applied cycle.
- Note that t_{DDKMHM} follows the symbol conventions described in note 1. For example, t_{DDKMHM} describes the DDR timing (DD) from the rising edge of the MCK(n) clock (KH) until the MDQS signal is valid (MH). t_{DDKMHM} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. In source synchronous mode, this is typically set to the same delay as the clock adjust in the CLK_CNTL register. The timing parameters listed in the table assume that these two parameters have been set to the same adjustment value. Refer *MPC8360E PowerQUICC II Pro Integrated Communications Processor Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.
- Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the device.
- All outputs are referenced to the rising edge of MCK(n) at the pins of the device. Note that t_{DDKHMP} follows the symbol conventions described in note 1.
- AC timing values are based on the DDR data rate, which is twice the DDR memory bus frequency.
- In rev. 2.0 silicon, t_{DDKMHM} maximum meets the specification of 0.6 ns. In rev. 2.0 silicon, due to errata, t_{DDKMHM} minimum is -0.9 ns. Refer to Errata DDR18 in *Chip Errata for the MPC8360E, Rev. 1*.

This figure shows the DDR SDRAM output timing for address skew with respect to any MCK.

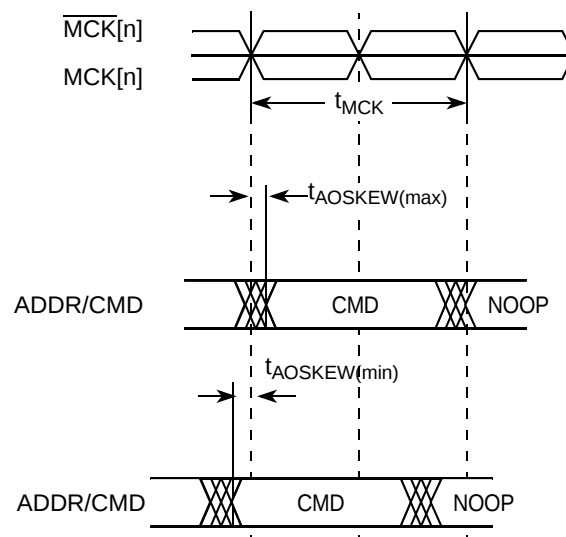


Figure 7. Timing Diagram for t_{AOSKEW} Measurement

Physical Layer Device Specification Version 1.2a (9/22/2000). The electrical characteristics for the MDIO and MDC are specified in [Section 8.3, “Ethernet Management Interface Electrical Characteristics.”](#)

8.1.1 10/100/1000 Ethernet DC Electrical Characteristics

The electrical characteristics specified here apply to media independent interface (MII), reduced gigabit media independent interface (RGMII), reduced ten-bit interface (RTBI), reduced media independent interface (RMII) signals, management data input/output (MDIO) and management data clock (MDC).

The MII and RMII interfaces are defined for 3.3 V, while the RGMII and RTBI interfaces can be operated at 2.5 V. The RGMII and RTBI interfaces follow the *Reduced Gigabit Media-Independent Interface (RGMII) Specification Version 1.3*. The RMII interface follows the *RMII Consortium RMII Specification Version 1.2*.

Table 25. RGMII/RTBI, GMII, TBI, MII, and RMII DC Electrical Characteristics (when operating at 3.3 V)

Parameter	Symbol	Conditions		Min	Max	Unit	Notes
Supply voltage 3.3 V	V_{DD}	—		2.97	3.63	V	1
Output high voltage	V_{OH}	$I_{OH} = -4.0 \text{ mA}$	$V_{DD} = \text{Min}$	2.40	$V_{DD} + 0.3$	V	—
Output low voltage	V_{OL}	$I_{OL} = 4.0 \text{ mA}$	$V_{DD} = \text{Min}$	GND	0.50	V	—
Input high voltage	V_{IH}	—	—	2.0	$V_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	—	—	-0.3	0.90	V	—
Input current	I_{IN}	$0 \text{ V} \leq V_{IN} \leq V_{DD}$		—	± 10	μA	—

Note:

1. GMII/II pins that are not needed for RGMII, RMII, or RTBI operation are powered by the OV_{DD} supply.

Table 26. RGMII/RTBI DC Electrical Characteristics (when operating at 2.5 V)

Parameters	Symbol	Conditions		Min	Max	Unit
Supply voltage 2.5 V	V_{DD}	—		2.37	2.63	V
Output high voltage	V_{OH}	$I_{OH} = -1.0 \text{ mA}$	$V_{DD} = \text{Min}$	2.00	$V_{DD} + 0.3$	V
Output low voltage	V_{OL}	$I_{OL} = 1.0 \text{ mA}$	$V_{DD} = \text{Min}$	GND - 0.3	0.40	V
Input high voltage	V_{IH}	—	$V_{DD} = \text{Min}$	1.7	$V_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	$V_{DD} = \text{Min}$	-0.3	0.70	V
Input current	I_{IN}	$0 \text{ V} \leq V_{IN} \leq V_{DD}$		—	± 10	μA

8.2 GMII, MII, RMII, TBI, RGMII, and RTBI AC Timing Specifications

The AC timing specifications for GMII, MII, TBI, RGMII, and RTBI are presented in this section.

8.2.1 GMII Timing Specifications

This sections describe the GMII transmit and receive AC timing specifications.

8.2.4.1 TBI Transmit AC Timing Specifications

This table provides the TBI transmit AC timing specifications.

Table 33. TBI Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
GTX_CLK clock period	t_{TTX}	—	8.0	—	ns	—
GTX_CLK duty cycle	t_{TTXH}/t_{TTX}	40	—	60	%	—
GTX_CLK to TBI data TCG[9:0] delay	t_{TTKHDV} t_{TTKHDX}	1.0 —	—	— 5.0	ns	3
GTX_CLK clock rise time, (20% to 80%)	t_{TTXR}	—	—	1.0	ns	—
GTX_CLK clock fall time, (80% to 20%)	t_{TTXF}	—	—	1.0	ns	—
GTX_CLK125 reference clock period	t_{G125}	—	8.0	—	ns	2
GTX_CLK125 reference clock duty cycle	t_{G125H}/t_{G125}	45	—	55	ns	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. This symbol is used to represent the external GTX_CLK125 and does not follow the original symbol naming convention.
3. In rev. 2.0 silicon, due to errata, t_{TTKHDV} minimum is 0.7 ns for UCC1. Refer to Errata *QE_ENET19* in *Chip Errata for the MPC8360E, Rev. 1*.

This figure shows the TBI transmit AC timing diagram.

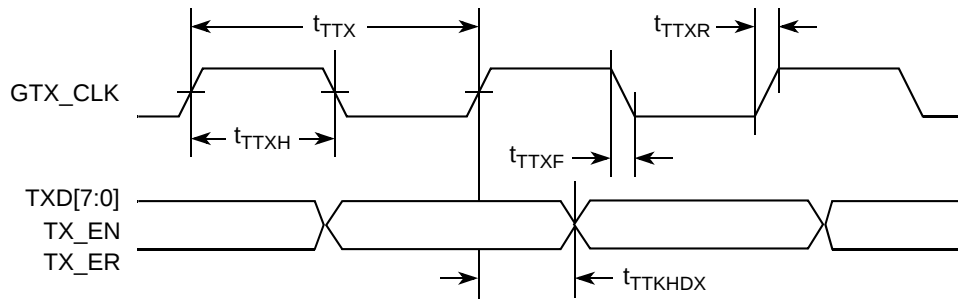


Figure 18. TBI Transmit AC Timing Diagram

8.2.5 RGMII and RTBI AC Timing Specifications

This table presents the RGMII and RTBI AC timing specifications.

Table 35. RGMII and RTBI AC Timing Specifications

At recommended operating conditions with LV_{DD} of 2.5 V $\pm$ 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
Data to clock output skew (at transmitter)	$t_{SKRGTKHDX}$ $t_{SKRGTKHDV}$	−0.5 —	—	— 0.5	ns	7
Data to clock input skew (at receiver)	$t_{SKRGDXKH}$ $t_{SKRGDVKH}$	1.0 —	—	— 2.6	ns	2
Clock cycle duration	t_{RGT}	7.2	8.0	8.8	ns	3
Duty cycle for 1000Base-T	t_{RGTH}/t_{RGT}	45	50	55	%	4, 5
Duty cycle for 10BASE-T and 100BASE-TX	t_{RGTH}/t_{RGT}	40	50	60	%	3, 5
Rise time (20–80%)	t_{RGTR}	—	—	0.75	ns	—
Fall time (20–80%)	t_{RGTF}	—	—	0.75	ns	—
GTX_CLK125 reference clock period	t_{G125}	—	8.0	—	ns	6
GTX_CLK125 reference clock duty cycle	t_{G125H}/t_{G125}	47	—	53	%	—

Notes:

- Note that, in general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII and RTBI timing. For example, the subscript of t_{RGT} represents the TBI (T) receive (Rx) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
- This implies that PC board design requires clocks to be routed such that an additional trace delay of greater than 1.5 ns can be added to the associated clock signal.
- For 10 and 100 Mbps, t_{RGT} scales to 400 ns $\pm$ 40 ns and 40 ns $\pm$ 4 ns, respectively.
- Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.
- Duty cycle reference is $LV_{DD}/2$.
- This symbol is used to represent the external GTX_CLK125 and does not follow the original symbol naming convention.
- In rev. 2.0 silicon, due to errata, $t_{SKRGTKHDX}$ minimum is −2.3 ns and $t_{SKRGTKHDV}$ maximum is 1 ns for UCC1, 1.2 ns for UCC2 option 1, and 1.8 ns for UCC2 option 2. In rev. 2.1 silicon, due to errata, $t_{SKRGTKHDX}$ minimum is −0.65 ns for UCC2 option 1 and −0.9 for UCC2 option 2, and $t_{SKRGTKHDV}$ maximum is 0.75 ns for UCC1 and UCC2 option 1 and 0.85 for UCC2 option 2. Refer to Errata QE_ENET10 in *Chip Errata for the MPC8360E, Rev. 1*. UCC1 does meet $t_{SKRGTKHDX}$ minimum for rev. 2.1 silicon.

8.3.3 IEEE 1588 Timer AC Specifications

This table provides the IEEE 1588 timer AC specifications.

Table 38. IEEE 1588 Timer AC Specifications

Parameter	Symbol	Min	Max	Unit	Notes
Timer clock frequency	t_{TMRCK}	0	70	MHz	1
Input setup to timer clock	t_{TMRCKS}	—	—	—	2, 3
Input hold from timer clock	t_{TMRCKH}	—	—	—	2, 3
Output clock to output valid	t_{GCLKNV}	0	6	ns	—
Timer alarm to output valid	t_{TMRAL}	—	—	—	2

Notes:

1. The timer can operate on rtc_clock or tmr_clock. These clocks get muxed and any one of them can be selected. The minimum and maximum requirement for both rtc_clock and tmr_clock are the same.
2. These are asynchronous signals.
3. Inputs need to be stable at least one TMR clock.

9 Local Bus

This section describes the DC and AC electrical specifications for the local bus interface of the MPC8360E/58E.

9.1 Local Bus DC Electrical Characteristics

This table provides the DC electrical characteristics for the local bus interface.

Table 39. Local Bus DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	$OV_{DD} + 0.3$	V
Low-level input voltage	V_{IL}	-0.3	0.8	V
High-level output voltage, $I_{OH} = -100 \mu A$	V_{OH}	$OV_{DD} - 0.4$	—	V
Low-level output voltage, $I_{OL} = 100 \mu A$	V_{OL}	—	0.2	V
Input current	I_{IN}	—	± 10	μA

9.2 Local Bus AC Electrical Specifications

This table describes the general timing parameters of the local bus interface of the device.

Table 40. Local Bus General Timing Parameters—DLL Enabled

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	7.5	—	ns	2
Input setup to local bus clock (except LUPWAIT)	$t_{LBIVKH1}$	1.7	—	ns	3, 4
LUPWAIT input setup to local bus clock	$t_{LBIVKH2}$	1.9	—	ns	3, 4
Input hold from local bus clock (except LUPWAIT)	$t_{LBIXKH1}$	1.0	—	ns	3, 4

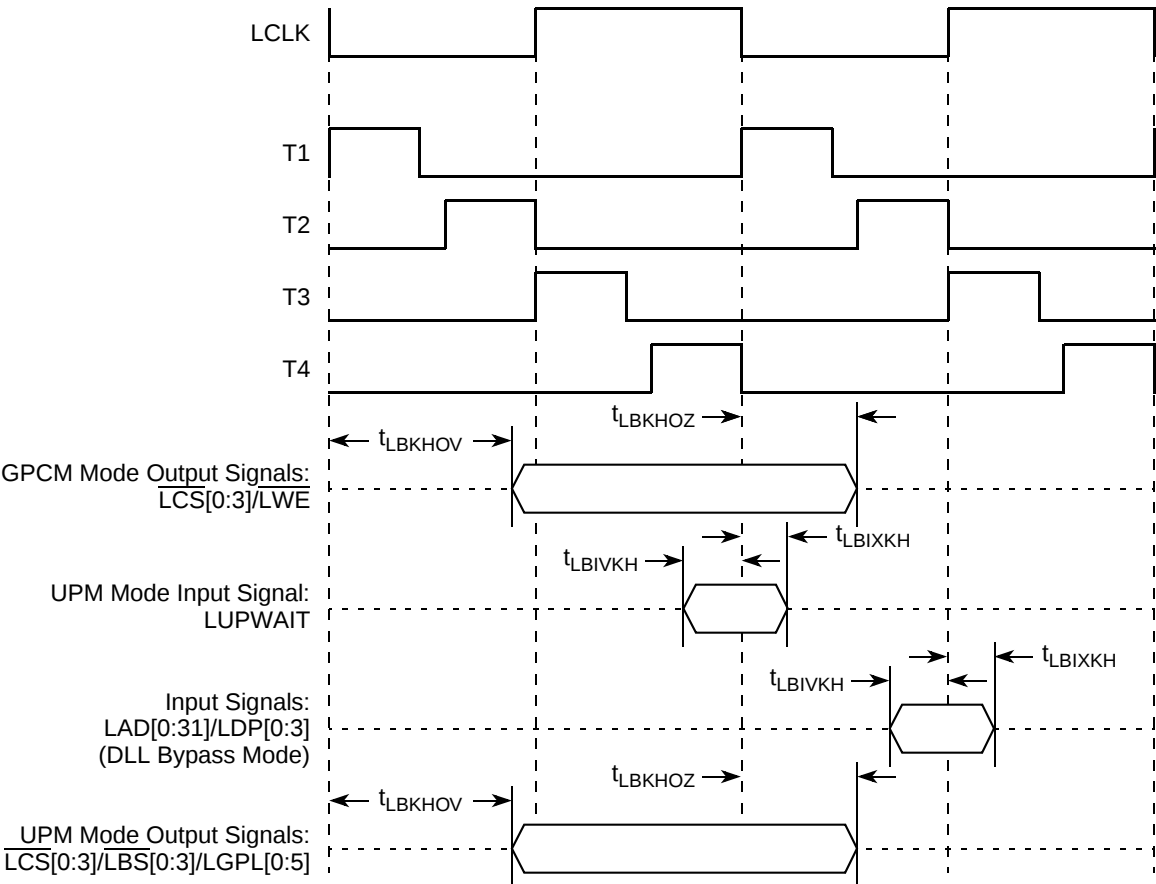


Figure 27. Local Bus Signals, GPCM/UPM Signals for LCRR[CLKDIV] = 4 (DLL Bypass Mode)

This figure provides the test access port timing diagram.

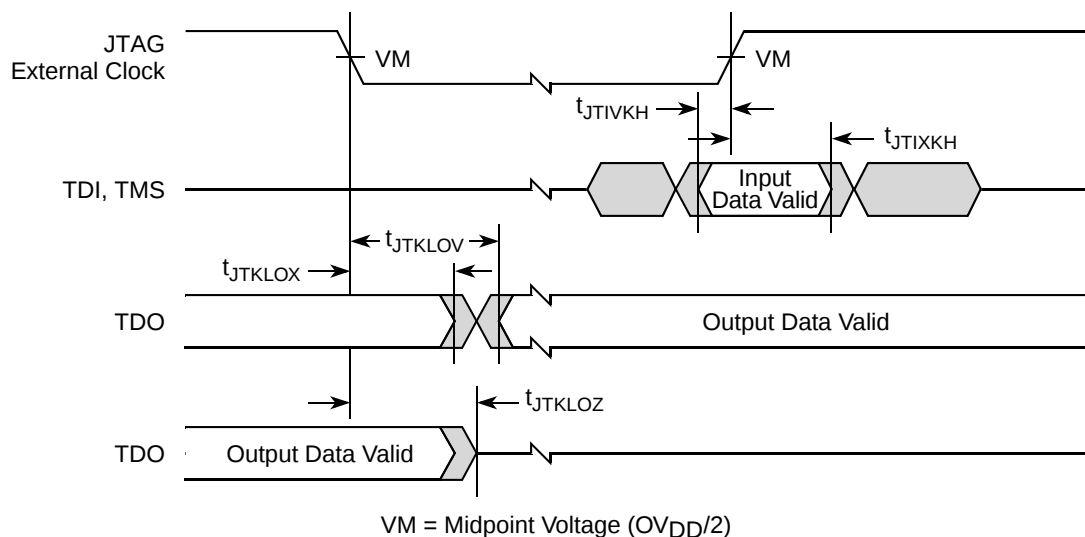


Figure 33. Test Access Port Timing Diagram

11 I²C

This section describes the DC and AC electrical characteristics for the I²C interface of the MPC8360E/58E.

11.1 I²C DC Electrical Characteristics

This table provides the DC electrical characteristics for the I²C interface of the device.

Table 44. I²C DC Electrical Characteristics

At recommended operating conditions with OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V_{IH}	$0.7 \times OV_{DD}$	$OV_{DD} + 0.3$	V	—
Input low voltage level	V_{IL}	-0.3	$0.3 \times OV_{DD}$	V	—
Low level output voltage	V_{OL}	0	0.4	V	1
Output fall time from $V_{IH}(\text{min})$ to $V_{IL}(\text{max})$ with a bus capacitance from 10 to 400 pF	t_{I2KLKV}	$20 + 0.1 \times C_B$	250	ns	2
Pulse width of spikes which must be suppressed by the input filter	t_{I2KHKL}	0	50	ns	3
Capacitance for each I/O pin	C_I	—	10	pF	—
Input current ($0\text{ V} \leq V_{IN} \leq OV_{DD}$)	I_{IN}	—	± 10	μA	4

Notes:

- Output voltage (open drain or open collector) condition = 3 mA sink current.
- C_B = capacitance of one bus line in pF.
- Refer to the *MPC8360E Integrated Communications Processor Reference Manual* for information on the digital filter used.
- I/O pins obstruct the SDA and SCL lines if OV_{DD} is switched off.

This figure shows the PCI input AC timing conditions.

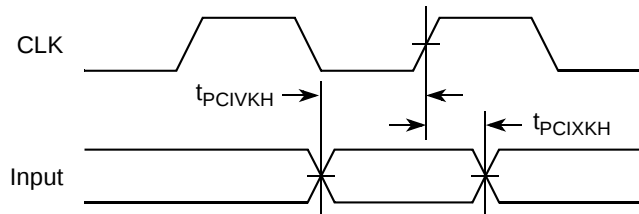


Figure 37. PCI Input AC Timing Measurement Conditions

This figure shows the PCI output AC timing conditions.

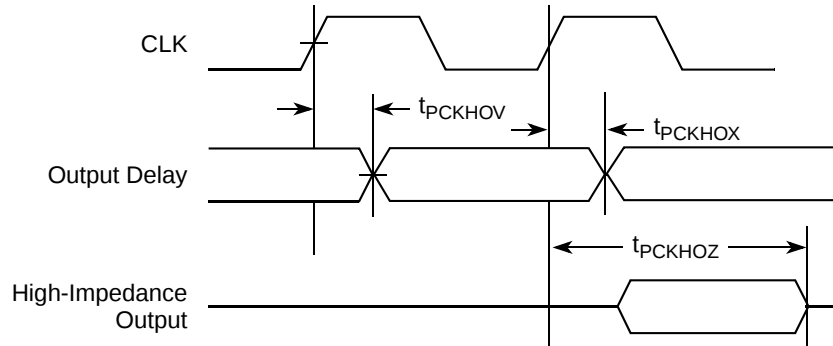


Figure 38. PCI Output AC Timing Measurement Condition

13 Timers

This section describes the DC and AC electrical specifications for the timers of the MPC8360E/58E.

13.1 Timers DC Electrical Characteristics

This table provides the DC electrical characteristics for the device timer pins, including TIN , $\overline{TOUT}$, $\overline{TGATE}$, and RTC_CLK .

Table 49. Timers DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	$I_{OH} = -6.0 \text{ mA}$	2.4	—	V
Output low voltage	V_{OL}	$I_{OL} = 6.0 \text{ mA}$	—	0.5	V
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.4	V
Input high voltage	V_{IH}	—	2.0	$OV_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	-0.3	0.8	V
Input current	I_{IN}	$0 \text{ V} \leq V_{IN} \leq OV_{DD}$	—	± 10	μA

13.2 Timers AC Timing Specifications

This table provides the timer input and output AC timing specifications.

Table 50. Timers Input AC Timing Specifications¹

Characteristic	Symbol ²	Typ	Unit
Timers inputs—minimum pulse width	t_{TIWID}	20	ns

Notes:

- Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of CLKIN. Timings are measured at the pin.
- Timers inputs and outputs are asynchronous to any visible clock. Timers outputs should be synchronized before use by any external synchronous logic. Timers inputs are required to be valid for at least t_{TIWID} ns to ensure proper operation.

This figure provides the AC test load for the timers.

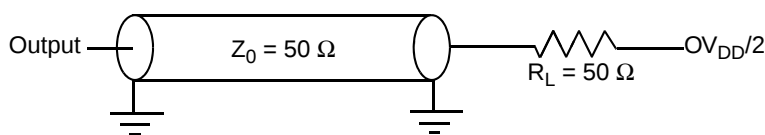


Figure 39. Timers AC Test Load

14 GPIO

This section describes the DC and AC electrical specifications for the GPIO of the MPC8360E/58E.

14.1 GPIO DC Electrical Characteristics

This table provides the DC electrical characteristics for the device GPIO.

Table 51. GPIO DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit	Notes
Output high voltage	V_{OH}	$I_{OH} = -6.0 \text{ mA}$	2.4	—	V	1
Output low voltage	V_{OL}	$I_{OL} = 6.0 \text{ mA}$	—	0.5	V	1
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.4	V	1
Input high voltage	V_{IH}	—	2.0	$OV_{DD} + 0.3$	V	1
Input low voltage	V_{IL}	—	-0.3	0.8	V	—
Input current	I_{IN}	$0 \text{ V} \leq V_{IN} \leq OV_{DD}$	—	± 10	μA	—

Note:

- This specification applies when operating from 3.3-V supply.

Table 66. MPC8360E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
MEMC1_MCKE[0:1]	AL32, AU33	O	GV _{DD}	3
MEMC1_MCK[0:1]	AK37, AT37	O	GV _{DD}	—
MEMC1_MCK[2:3]/ MEMC2_MCK[0:1]	AN1, AR2	O	GV _{DD}	—
MEMC1_MCK[4:5]/ MEMC2_MCKE[0:1]	AN25, AK1	O	GV _{DD}	—
MEMC1_MCK[0:1]	AL37, AT36	O	GV _{DD}	—
MEMC1_MCK[2:3]/ MEMC2_MCK[0:1]	AP2, AT2	O	GV _{DD}	—
MEMC1_MCK[4]/ MEMC2_MDM[8]	AN24	O	GV _{DD}	—
MEMC1_MCK[5]/ MEMC2_MDQS[8]	AL1	O	GV _{DD}	—
MDIC[0:1]	AH6, AP30	I/O	GV _{DD}	10
Secondary DDR SDRAM Memory Controller Interface				
MEMC2_MECC[0:7]	AN16, AP18, AM16, AM17, AN17, AP13, AP15, AN13	I/O	GV _{DD}	—
MEMC2_MBA[0:2]	AU12, AU15, AU13	O	GV _{DD}	—
MEMC2_MA[0:14]	AT12, AP11, AT13, AT14, AR13, AR15, AR16, AT16, AT18, AT17, AP10, AR20, AR17, AR14, AR11	O	GV _{DD}	—
MEMC2_MWE	AU10	O	GV _{DD}	—
MEMC2_MRAS	AT11	O	GV _{DD}	—
MEMC2_MCAS	AU11	O	GV _{DD}	—
PCI				
PCI_INTA/IRQ_OUT/CE_PF[5]	A20	I/O	LV _{DD2}	2
PCI_RESET_OUT/CE_PF[6]	E19	I/O	LV _{DD2}	—
PCI_AD[31:30]/CE_PG[31:30]	D20, D21	I/O	LV _{DD2}	—
PCI_AD[29:25]/CE_PG[29:25]	A24, B23, C23, E23, A26	I/O	OV _{DD}	—
PCI_AD[24]/CE_PG[24]	B21	I/O	LV _{DD2}	—
PCI_AD[23:0]/CE_PG[23:0]	C24, C25, D25, B25, E24, F24, A27, A28, F27, A30, C30, D30, E29, B31, C31, D31, D32, A32, C33, B33, F30, E31, A34, D33	I/O	OV _{DD}	—
PCI_C/BE[3:0]/CE_PF[10:7]	E22, B26, E28, F28	I/O	OV _{DD}	—
PCI_PAR/CE_PF[11]	D28	I/O	OV _{DD}	—
PCI_FRAME/CE_PF[12]	D26	I/O	OV _{DD}	5
PCI_TRDY/CE_PF[13]	C27	I/O	OV _{DD}	5
PCI_IRDY/CE_PF[14]	C28	I/O	OV _{DD}	5
PCI_STOP/CE_PF[15]	B28	I/O	OV _{DD}	5

Table 66. MPC8360E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PMC				
$\overline{\text{QUIESCE}}$	B36	O	OV_{DD}	—
System Control				
$\overline{\text{PORESET}}$	L37	I	OV_{DD}	—
$\overline{\text{HRESET}}$	L36	I/O	OV_{DD}	1
$\overline{\text{SRESET}}$	M33	I/O	OV_{DD}	2
Thermal Management				
THERM0	AP19	I	GV_{DD}	—
THERM1	AT31	I	GV_{DD}	—
Power and Ground Signals				
$\text{AV}_{\text{DD}1}$	K35	Power for LBIU DLL (1.2 V)	$\text{AV}_{\text{DD}1}$	—
$\text{AV}_{\text{DD}2}$	K36	Power for CE PLL (1.2 V)	$\text{AV}_{\text{DD}2}$	—
$\text{AV}_{\text{DD}5}$	AM29	Power for e300 PLL (1.2 V)	$\text{AV}_{\text{DD}5}$	—
$\text{AV}_{\text{DD}6}$	K37	Power for system PLL (1.2 V)	$\text{AV}_{\text{DD}6}$	—
GND	A2, A8, A13, A19, A22, A25, A31, A33, A36, B7, B12, B24, B27, B30, C4, C6, C9, C15, C26, C32, D3, D8, D11, D14, D17, D19, D23, D27, E7, E13, E25, E30, E36, F4, F37, G34, H1, H5, H32, H33, J4, J32, J37, K1, L3, L5, L33, L34, M1, M34, M35, N37, P2, P5, P35, P36, R4, T3, U1, U5, U35, V37, W1, W4, W33, W36, Y34, AA3, AA5, AC3, AC32, AC35, AD1, AD37, AE4, AE34, AE36, AF33, AG4, AG6, AG32, AH35, AJ1, AJ4, AJ32, AJ35, AJ37, AK36, AL3, AL34, AM4, AN6, AN23, AN30, AP8, AP12, AP14, AP16, AP17, AP20, AP25, AR6, AR8, AR9, AR19, AR24, AR31, AR35, AR37, AT4, AT10, AT19, AT20, AT25, AU14, AU22, AU28, AU35	—	—	—
GV_{DD}	AD4, AE3, AF1, AF5, AF35, AF37, AG2, AG36, AH33, AH34, AK5, AM1, AM35, AM37, AN2, AN10, AN11, AN12, AN14, AN32, AN36, AP5, AP23, AP28, AR1, AR7, AR10, AR12, AR21, AR25, AR27, AR33, AT15, AT22, AT28, AT33, AU2, AU5, AU16, AU31, AU36	Power for DDR DRAM I/O voltage (2.5 or 1.8 V)	GV_{DD}	—

Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{IRQ}}[4:5]$	G33, G32	I/O	OV_{DD}	—
$\overline{\text{IRQ}}[6]/\overline{\text{LCS}}[6]/\overline{\text{CKSTOP_OUT}}$	E35	I/O	OV_{DD}	—
$\overline{\text{IRQ}}[7]/\overline{\text{LCS}}[7]/\overline{\text{CKSTOP_IN}}$	H36	I/O	OV_{DD}	—
DUART				
UART1_SOUT/M1SRCID[0]/M2SRCID[0]/LSRCID[0]	E32	O	OV_{DD}	—
UART1_SIN/M1SRCID[1]/M2SRCID[1]/LSRCID[1]	B34	I/O	OV_{DD}	—
$\overline{\text{UART1_CTS}}$ /M1SRCID[2]/M2SRCID[2]/LSRCID[2]	C34	I/O	OV_{DD}	—
$\overline{\text{UART1_RTS}}$ /M1SRCID[3]/M2SRCID[3]/LSRCID[3]	A35	O	OV_{DD}	—
I²C Interface				
IIC1_SDA	D34	I/O	OV_{DD}	2
IIC1_SCL	B35	I/O	OV_{DD}	2
IIC2_SDA	E33	I/O	OV_{DD}	2
IIC2_SCL	C35	I/O	OV_{DD}	2
QUICC Engine				
CE_PA[0]	F8	I/O	$\text{LV}_{\text{DD}0}$	—
CE_PA[1:2]	AH1, AG5	I/O	OV_{DD}	—
CE_PA[3:7]	F6, D4, C3, E5, A3	I/O	$\text{LV}_{\text{DD}0}$	—
CE_PA[8]	AG3	I/O	OV_{DD}	—
CE_PA[9:12]	F7, B3, E6, B4	I/O	$\text{LV}_{\text{DD}0}$	—
CE_PA[13:14]	AG1, AF6	I/O	OV_{DD}	—
CE_PA[15]	B2	I/O	$\text{LV}_{\text{DD}0}$	—
CE_PA[16]	AF4	I/O	OV_{DD}	—
CE_PA[17:21]	B16, A16, E17, A17, B17	I/O	$\text{LV}_{\text{DD}1}$	—
CE_PA[22]	AF3	I/O	OV_{DD}	—
CE_PA[23:26]	C18, D18, E18, A18	I/O	$\text{LV}_{\text{DD}1}$	—
CE_PA[27:28]	AF2, AE6	I/O	OV_{DD}	—
CE_PA[29]	B19	I/O	$\text{LV}_{\text{DD}1}$	—
CE_PA[30]	AE5	I/O	OV_{DD}	—
CE_PA[31]	F16	I/O	$\text{LV}_{\text{DD}1}$	—

Table 72. CSB Frequency Options (continued)

CFG_CLKIN_DIV at Reset ¹	SPMF	csb_clk: Input Clock Ratio ²	Input Clock Frequency (MHz) ²			
			16.67	25	33.33	66.67
			csb_clk Frequency (MHz)			
Low	0110	6:1	100	150	200	
Low	0111	7:1	116	175	233	
Low	1000	8:1	133	200	266	
Low	1001	9:1	150	225	300	
Low	1010	10:1	166	250	333	
Low	1011	11:1	183	275		
Low	1100	12:1	200	300		
Low	1101	13:1	216	325		
Low	1110	14:1	233			
Low	1111	15:1	250			
Low	0000	16:1	266			
High	0010	2:1				133
High	0011	3:1				100
High	0100	4:1				133
High	0101	5:1				166
High	0110	6:1				200
High	0111	7:1				233
High	1000	8:1				
High	1001	9:1				
High	1010	10:1				
High	1011	11:1				
High	1100	12:1				
High	1101	13:1				
High	1110	14:1				
High	1111	15:1				
High	0000	16:1				

¹ CFG_CLKIN_DIV is only used for host mode; CLKIN must be tied low and CFG_CLKIN_DIV must be pulled down (low) in agent mode.

² CLKIN is the input clock in host mode; PCI_CLK is the input clock in agent mode.

Table 76. Suggested PLL Configurations (continued)

Conf No. ¹	SPMF	CORE PLL	CEPMF	CEPDF	Input Clock Freq (MHz)	CSB Freq (MHz)	Core Freq (MHz)	QUICC Engine Freq (MHz)	400 (MHz)	533 (MHz)	667 (MHz)
c5	æ	æ	10000	0	33	—	—	533	—	∞	∞
c6	æ	æ	10001	0	33	—	—	566	—	—	∞
66 MHz CLKIN/PCI_SYNC_IN Options											
s1h	0011	0000110	æ	æ	66	200	400	—	∞	∞	∞
s2h	0011	0000101	æ	æ	66	200	500	—	—	∞	∞
s3h	0011	0000110	æ	æ	66	200	600	—	—	—	∞
s4h	0100	0000011	æ	æ	66	266	400	—	∞	∞	∞
s5h	0100	0000100	æ	æ	66	266	533	—	—	∞	∞
s6h	0100	0000101	æ	æ	66	266	667	—	—	—	∞
s7h	0101	0000010	æ	æ	66	333	333	—	∞	∞	∞
s8h	0101	0000011	æ	æ	66	333	500	—	—	∞	∞
s9h	0101	0000100	æ	æ	66	333	667	—	—	—	∞
c1h	æ	æ	00101	0	66	—	—	333	∞	∞	∞
c2h	æ	æ	00110	0	66	—	—	400	∞	∞	∞
c3h	æ	æ	00111	0	66	—	—	466	—	∞	∞
c4h	æ	æ	01000	0	66	—	—	533	—	∞	∞
c5h	æ	æ	01001	0	66	—	—	600	—	—	∞

Note:

1. The Conf No. consist of prefix, an index and a postfix. The prefix “s” and “c” stands for “sysset” and “ce” respectively. The postfix “h” stands for “high input clock.”The index is a serial number.

The following steps describe how to use above table. See [Example 1](#).

2. Choose the up or down sections in the table according to input clock rate 33 MHz or 66 MHz.
3. Select a suitable CSB and core clock rates from [Table 76](#). Copy the SPMF and CORE PLL configuration bits.
4. Select a suitable QUICC Engine block clock rate from [Table 76](#). Copy the CEPMPF and CEPDF configuration bits.
5. Insert the chosen SPMF, COREPLL, CEPMPF and CEPDF to the RCWL fields, respectively.

22.3.1 Experimental Determination of the Junction Temperature with a Heat Sink

When heat sink is used, the junction temperature is determined from a thermocouple inserted at the interface between the case of the package and the interface material. A clearance slot or hole is normally required in the heat sink. Minimizing the size of the clearance is important to minimize the change in thermal performance caused by removing part of the thermal interface to the heat sink. Because of the experimental difficulties with this technique, many engineers measure the heat sink temperature and then back calculate the case temperature using a separate measurement of the thermal resistance of the interface. From this case temperature, the junction temperature is determined from the junction-to-case thermal resistance.

$$T_J = T_C + (R_{\theta JC} \times P_D)$$

where:

T_J = junction temperature (°C)

T_C = case temperature of the package (°C)

$R_{\theta JC}$ = junction to case thermal resistance (°C/W)

P_D = power dissipation (W)

23 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8360E/58E. Additional information can be found in *MPC8360E/MPC8358E PowerQUICC Design Checklist* (AN3097).

23.1 System Clocking

The device includes two PLLs, as follows.

- The platform PLL (AV_{DD1}) generates the platform clock from the externally supplied CLKIN input. The frequency ratio between the platform and CLKIN is selected using the platform PLL ratio configuration bits as described in [Section 21.1, “System PLL Configuration.”](#)
- The e300 core PLL (AV_{DD2}) generates the core clock as a slave to the platform clock. The frequency ratio between the e300 core clock and the platform clock is selected using the e300 PLL ratio configuration bits as described in [Section 21.2, “Core PLL Configuration.”](#)

23.2 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins (AV_{DD1}, AV_{DD2}, respectively). The AV_{DD} level should always be equivalent to V_{DD}, and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide five independent filter circuits as illustrated in [Figure 56](#), one to each of the five AV_{DD} pins. By providing independent filters to each PLL, the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of package, without the inductance of vias.

Table 81. SVR Settings (continued)

Device	Package	SVR (Rev. 2.0)	SVR (Rev. 2.1)
MPC8358E	TBGA	0x804A_0020	0x804A_0021
MPC8358	TBGA	0x804B_0020	0x804B_0021

25 Document Revision History

This table provides a revision history for this document.

Table 82. Revision History

Rev. Number	Date	Substantive Change(s)
5	09/2011	• Section 2.2.1, "Power-Up Sequencing", added the current limitation "3A to 5A" for the excessive current. • Section 2.1.2, "Power Supply Voltage Specification", Updated the Characteristic for TBGA (MPC8358 & MPC8360 Device) with specific frequency for Core and PLL voltages. • Added table footnote 3 to Table 2. • Applied table footnotes 1 and 2 to Table 10. • Removed table footnotes from Table 19. • Applied table footnote 8 to the last row of Table 40. • Applied table footnotes 8 and 9 to Table 41. • Applied table footnotes 2 and 3 to Table 45. • Removed table footnotes from Table 46. • Applied table footnote to last three rows of Table 65.
4	01/2011	• Updated references to the LCRR register throughout • Removed references to DDR DLL mode in Section 6.2.2, "DDR and DDR2 SDRAM Output AC Timing Specifications". • Changed "Junction-to-Case" to "Junction-to-Ambient" in Section 22.2.4, "Heat Sinks and Junction-to-Ambient Thermal Resistance", and Table 78, "Heat Sinks and Junction-to-Ambient Thermal Resistance of TBGA Package", titles.

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